

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. H-957-04		SERIAL NO.	
<b>LIST OF DOCUMENTS CITED BY APPLICANT</b> <i>(Use several sheets if necessary)</i>				APPLICANT T. MATSUURA et al		GROUP	
				FILING DATE September 25, 2003			
<b>U.S. PATENT DOCUMENTS</b>							
* EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE <i>(If Appropriate)</i>	
	AA	5,026,669	06/25/91	Shinohara			
	AB	5,327,104	07/05/94	Kikushima			
	AC	5,731,231	03/24/98	Miyajima			
	AD	5,973,395	10/26/99	Suzuki et al			
	AE	6,208,020	03/27/01	Minamio et al			
	AF	6,399,423	06/2002	Matsuura et al			
	AG	6,208,020	03/2001	Minamio et al			
	AH						
	AI						
	AJ						
	AK						
<b>FOREIGN PATENT DOCUMENTS</b>							
	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATIO YES NO	
	AL	11-195743	07/21/99	Japan		<input type="checkbox"/>	<input type="checkbox"/>
	AM	2-240940	09/25/90	Japan		<input type="checkbox"/>	<input type="checkbox"/>
	AN					<input type="checkbox"/>	<input type="checkbox"/>
	AO					<input type="checkbox"/>	<input type="checkbox"/>
	AP					<input type="checkbox"/>	<input type="checkbox"/>
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AR	"Semiconductor Assembling/Testing Technique of '99", Extra Issue of Monthly Semiconductor World, July 27, 1998.					
	AS						
	AT						
EXAMINER				DATE CONSIDERED			

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form next communication to applicant.